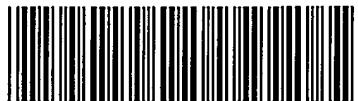


**Search Notes****Application/Control No.**

10/803,183

**Examiner**

Hien N. Nguyen

**Applicant(s)/Patent under Reexamination**

CHEN ET AL.

**Art Unit**

2824

<b>SEARCHED</b>			
Class	Subclass	Date	Examiner
365	185.17	7/25/2005	HN
365	185.29		
365	185.33		
257	314		
257	315		
257	316		
257	317	↓	↓

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/25/2005	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner